

<b>Notice of References Cited</b>		Application/Control No. 10/044,565	Applicant(s)/Patent Under Reexamination KUKREJA ET AL.	
		Examiner Greg Bengzon	Art Unit 2144	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0163438 A1	08-2003	Barnett et al.	707/1
	B	US-2002/0138572 A1	09-2002	Delany et al.	709/204
	C	US-2002/0128995 A1	09-2002	Muntz et al.	707/1
	D	US-2002/0133579 A1	09-2002	Bernhardt et al.	709/223
	E	US-2002/0165960 A1	11-2002	Chan, Christine Wai Han	709/225
	F	US-6,904,600 B1	06-2005	James et al.	719/328
	G	US-6,742,114 B1	05-2004	Carter et al.	713/156
	H	US-2003/0131020 A1	07-2003	Karamanolis et al.	707/200
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

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